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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	36864
Number of I/O	93
Number of Gates	250000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/m1afs250-1pq208i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

## **Embedded Memories**

## Flash Memory Blocks

The flash memory available in each Fusion device is composed of one to four flash blocks, each 2 Mbits in density. Each block operates independently with a dedicated flash controller and interface. Fusion flash memory blocks combine fast access times (60 ns random access and 10 ns access in Read-Ahead mode) with a configurable 8-, 16-, or 32-bit datapath, enabling high-speed flash operation without wait states. The memory block is organized in pages and sectors. Each page has 128 bytes, with 33 pages comprising one sector and 64 sectors per block. The flash block can support multiple partitions. The only constraint on size is that partition boundaries must coincide with page boundaries. The flexibility and granularity enable many use models and allow added granularity in programming updates.

Fusion devices support two methods of external access to the flash memory blocks. The first method is a serial interface that features a built-in JTAG-compliant port, which allows in-system programmability during user or monitor/test modes. This serial interface supports programming of an AES-encrypted stream. Data protected with security measures can be passed through the JTAG interface, decrypted, and then programmed in the flash block. The second method is a soft parallel interface.

FPGA logic or an on-chip soft microprocessor can access flash memory through the parallel interface. Since the flash parallel interface is implemented in the FPGA fabric, it can potentially be customized to meet special user requirements. For more information, refer to the *CoreCFI Handbook*. The flash memory parallel interface provides configurable byte-wide (×8), word-wide (×16), or dual-word-wide (×32) data-port options. Through the programmable flash parallel interface, the on-chip and off-chip memories can be cascaded for wider or deeper configurations.

The flash memory has built-in security. The user can configure either the entire flash block or the small blocks to protect against unintentional or intrusive attempts to change or destroy the storage contents. Each on-chip flash memory block has a dedicated controller, enabling each block to operate independently.

The flash block logic consists of the following sub-blocks:

- Flash block Contains all stored data. The flash block contains 64 sectors and each sector contains 33 pages of data.
- Page Buffer Contains the contents of the current page being modified. A page contains 8 blocks of data.
- Block Buffer Contains the contents of the last block accessed. A block contains 128 data bits.
- ECC Logic The flash memory stores error correction information with each block to perform single-bit error correction and double-bit error detection on all data blocks.

### User Nonvolatile FlashROM

In addition to the flash blocks, Fusion devices have 1 Kbit of user-accessible, nonvolatile FlashROM on-chip. The FlashROM is organized as 8×128-bit pages. The FlashROM can be used in diverse system applications:

- Internet protocol addressing (wireless or fixed)
- System calibration settings
- Device serialization and/or inventory control
- Subscription-based business models (for example, set-top boxes)
- · Secure key storage for communications algorithms protected by security
- Asset management/tracking
- Date stamping
- Version management

The FlashROM is written using the standard IEEE 1532 JTAG programming interface. Pages can be individually programmed (erased and written). On-chip AES decryption can be used selectively over public networks to load data such as security keys stored in the FlashROM for a user design.

The FlashROM can be programmed (erased and written) via the JTAG programming interface, and its contents can be read back either through the JTAG programming interface or via direct FPGA core addressing.

## **Crystal Oscillator**

The Crystal Oscillator (XTLOSC) is source that generates the clock from an external crystal. The output of XTLOSC CLKOUT signal can be selected as an input to the PLL. Refer to the "Clock Conditioning Circuits" section for more details. The XTLOSC can operate in normal operations and Standby mode (RTC is running and 1.5 V is not present).

In normal operation, the internal FPGA\_EN signal is '1' as long as 1.5 V is present for VCC. As such, the internal enable signal, XTL\_EN, for Crystal Oscillator is enabled since FPGA\_EN is asserted. The XTL\_MODE has the option of using MODE or RTC\_MODE, depending on SELMODE.

During Standby, 1.5 V is not available, as such, and FPGA\_EN is '0'. SELMODE must be asserted in order for XTL\_EN to be enabled; hence XTL\_MODE relies on RTC\_MODE. SELMODE and RTC\_MODE must be connected to RTCXTLSEL and RTCXTLMODE from the AB respectively for correct operation during Standby (refer to the "Real-Time Counter System" section on page 2-31 for a detailed description).

The Crystal Oscillator can be configured in one of four modes:

- RC network, 32 KHz to 4 MHz
- Low gain, 32 to 200 KHz
- Medium gain, 0.20 to 2.0 MHz
- High gain, 2.0 to 20.0 MHz

In RC network mode, the XTAL1 pin is connected to an RC circuit, as shown in Figure 2-16 on page 2-18. The XTAL2 pin should be left floating. The RC value can be chosen based on Figure 2-18 for any desired frequency between 32 KHz and 4 MHz. The RC network mode can also accommodate an external clock source on XTAL1 instead of an RC circuit.

In Low gain, Medium gain, and High gain, an external crystal component or ceramic resonator can be added onto XTAL1 and XTAL2, as shown in Figure 2-16 on page 2-18. In the case where the Crystal Oscillator block is not used, the XTAL1 pin should be connected to GND and the XTAL2 pin should be left floating.



Note: \*Internal signal—does not exist in macro.

Figure 2-17 • XTLOSC Macro



## **Embedded Memories**

Fusion devices include four types of embedded memory: flash block, FlashROM, SRAM, and FIFO.

## **Flash Memory Block**

Fusion is the first FPGA that offers a flash memory block (FB). Each FB block stores 2 Mbits of data. The flash memory block macro is illustrated in Figure 2-32. The port pin name and descriptions are detailed on Table 2-19 on page 2-40. All flash memory block signals are active high, except for CLK and active low RESET. All flash memory operations are synchronous to the rising edge of CLK.



Figure 2-32 • Flash Memory Block

## Flash Memory Block Diagram

A simplified diagram of the flash memory block is shown in Figure 2-33.





The logic consists of the following sub-blocks:

Flash Array

Contains all stored data. The flash array contains 64 sectors, and each sector contains 33 pages of data.

Page Buffer

A page-wide volatile register. A page contains 8 blocks of data and an AUX block.

- Block Buffer
  - Contains the contents of the last block accessed. A block contains 128 data bits.
- ECC Logic

The FB stores error correction information with each block to perform single-bit error correction and double-bit error detection on all data blocks.



The third part of the Analog Quad is called the Gate Driver Block, and its output pin is named AG. This section is used to drive an external FET. There are two modes available: a High Current Drive mode and a Current Source Control mode. Both negative and positive voltage polarities are available, and in the current source control mode, four different current levels are available.

The fourth section of the Analog Quad is called the Temperature Monitor Block, and its input pin name is AT. This block is similar to the Voltage Monitor Block, except that it has an additional function: it can be used to monitor the temperature of an external diode-connected transistor. It has a modified prescaler and is limited to positive voltages only.

The Analog Quad can be configured during design time by Libero SoC; however, the ACM can be used to change the parameters of any of these I/Os during runtime. This type of change is referred to as a context switch. The Analog Quad is a modular structure that is replicated to generate the analog I/O resources. Each Fusion device supports between 5 and 10 Analog Quads.

The analog pads are numbered to clearly identify both the type of pad (voltage, current, gate driver, or temperature pad) and its corresponding Analog Quad (AV0, AC0, AG0, AT0, AV1, ..., AC9, AG9, and AT9). There are three types of input pads (AVx, ACx, and ATx) and one type of analog output pad (AGx). Since there can be up to 10 Analog Quads on a device, there can be a maximum of 30 analog input pads and 10 analog output pads.



Figure 2-65 • Analog Quad



## ADC Description

The Fusion ADC is a 12-bit SAR ADC. It offers a wide variety of features for different use models. Figure 2-80 shows a block diagram of the Fusion ADC.

- · Configurable resolution: 8-bit, 10-bit, and 12-bit mode
- DNL: 0.6 LSB for 10-bit mode
- INL: 0.4 LSB for 10-bit mode
- No missing code
- Internal VAREF = 2.56 V
- Maximum Sample Rate = 600 Ksps
- Power-up calibration and dynamic calibration after every sample to compensate for temperature drift over time



Figure 2-80 • ADC Simplified Block Diagram

## ADC Theory of Operation

An analog-to-digital converter is used to capture discrete samples of a continuous analog voltage and provide a discrete binary representation of the signal. Analog-to-digital converters are generally characterized in three ways:

- Input voltage range
- Resolution
- Bandwidth or conversion rate

The input voltage range of an ADC is determined by its reference voltage (VREF). Fusion devices include an internal 2.56 V reference, or the user can supply an external reference of up to 3.3 V. The following examples use the internal 2.56 V reference, so the full-scale input range of the ADC is 0 to 2.56 V.

The resolution (LSB) of the ADC is a function of the number of binary bits in the converter. The ADC approximates the value of the input voltage using 2n steps, where n is the number of bits in the converter. Each step therefore represents VREF÷ 2n volts. In the case of the Fusion ADC configured for 12-bit operation, the LSB is 2.56 V / 4096 = 0.625 mV.

Finally, bandwidth is an indication of the maximum number of conversions the ADC can perform each second. The bandwidth of an ADC is constrained by its architecture and several key performance characteristics.



#### **Offset Error**

Offset error indicates how well the actual transfer function matches the ideal transfer function at a single point. For an ideal ADC, the first transition occurs at 0.5 LSB above zero. The offset voltage is measured by applying an analog input such that the ADC outputs all zeroes and increases until the first transition occurs (Figure 2-86).



Figure 2-86 • Offset Error

#### Resolution

ADC resolution is the number of bits used to represent an analog input signal. To more accurately replicate the analog signal, resolution needs to be increased.

#### Sampling Rate

Sampling rate or sample frequency, specified in samples per second (sps), is the rate at which an ADC acquires (samples) the analog input.

#### SNR – Signal-to-Noise Ratio

SNR is the ratio of the amplitude of the desired signal to the amplitude of the noise signals at a given point in time. For a waveform perfectly reconstructed from digital samples, the theoretical maximum SNR (EQ 14) is the ratio of the full-scale analog input (RMS value) to the RMS quantization error (residual error). The ideal, theoretical minimum ADC noise is caused by quantization error only and results directly from the ADC's resolution (N bits):

$$SNR_{dB[MAX]} = 6.02_{dB} \times N + 1.76_{dB}$$

EQ 14

#### SINAD – Signal-to-Noise and Distortion

SINAD is the ratio of the rms amplitude to the mean value of the root-sum-square of the all other spectral components, including harmonics, but excluding DC. SINAD is a good indication of the overall dynamic performance of an ADC because it includes all components which make up noise and distortion.

#### **Total Harmonic Distortion**

THD measures the distortion content of a signal, and is specified in decibels relative to the carrier (dBc). THD is the ratio of the RMS sum of the selected harmonics of the input signal to the fundamental itself. Only harmonics within the Nyquist limit are included in the measurement.

## ADC Interface Timing

# Table 2-48 • ADC Interface Timing Commercial Temperature Range Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V

Parameter	Description	-2	-1	Std.	Units
t <sub>SUMODE</sub>	Mode Pin Setup Time	0.56	0.64	0.75	ns
t <sub>HDMODE</sub>	Mode Pin Hold Time	0.26	0.29	0.34	ns
t <sub>SUTVC</sub>	Clock Divide Control (TVC) Setup Time	0.68	0.77	0.90	ns
t <sub>HDTVC</sub>	Clock Divide Control (TVC) Hold Time	0.32	0.36	0.43	ns
t <sub>SUSTC</sub>	Sample Time Control (STC) Setup Time	1.58	1.79	2.11	ns
t <sub>HDSTC</sub>	Sample Time Control (STC) Hold Time	1.27	1.45	1.71	ns
t <sub>SUVAREFSEL</sub>	Voltage Reference Select (VAREFSEL) Setup Time	0.00	0.00	0.00	ns
t <sub>HDVAREFSEL</sub>	Voltage Reference Select (VAREFSEL) Hold Time	0.67	0.76	0.89	ns
t <sub>SUCHNUM</sub>	Channel Select (CHNUMBER) Setup Time	0.90	1.03	1.21	ns
t <sub>HDCHNUM</sub>	Channel Select (CHNUMBER) Hold Time	0.00	0.00	0.00	ns
t <sub>SUADCSTART</sub>	Start of Conversion (ADCSTART) Setup Time	0.75	0.85	1.00	ns
t <sub>HDADCSTART</sub>	Start of Conversion (ADCSTART) Hold Time	0.43	0.49	0.57	ns
t <sub>CK2QBUSY</sub>	Busy Clock-to-Q	1.33	1.51	1.78	ns
t <sub>CK2QCAL</sub>	Power-Up Calibration Clock-to-Q	0.63	0.71	0.84	ns
t <sub>CK2QVAL</sub>	Valid Conversion Result Clock-to-Q	3.12	3.55	4.17	ns
t <sub>CK2QSAMPLE</sub>	Sample Clock-to-Q	0.22	0.25	0.30	ns
t <sub>CK2QRESULT</sub>	Conversion Result Clock-to-Q	2.53	2.89	3.39	ns
t <sub>CLR2QBUSY</sub>	Busy Clear-to-Q	2.06	2.35	2.76	ns
t <sub>CLR2QCAL</sub>	Power-Up Calibration Clear-to-Q	2.15	2.45	2.88	ns
t <sub>CLR2QVAL</sub>	Valid Conversion Result Clear-to-Q	2.41	2.74	3.22	ns
t <sub>CLR2QSAMPLE</sub>	Sample Clear-to-Q	2.17	2.48	2.91	ns
t <sub>CLR2QRESULT</sub>	Conversion result Clear-to-Q	2.25	2.56	3.01	ns
t <sub>RECCLR</sub>	Recovery Time of Clear	0.00	0.00	0.00	ns
t <sub>REMCLR</sub>	Removal Time of Clear	0.63	0.72	0.84	ns
t <sub>MPWSYSCLK</sub>	Clock Minimum Pulse Width for the ADC	4.00	4.00	4.00	ns
t <sub>FMAXSYSCLK</sub>	Clock Maximum Frequency for the ADC	100.00	100.00	100.00	MHz



#### 2.5 V LVCMOS

Low-Voltage CMOS for 2.5 V is an extension of the LVCMOS standard (JESD8-5) used for general-purpose 2.5 V applications.

2.5 V LVCMOS	v	IL	v	н	VOL	VОН	IOL	юн	IOSL	IOSH	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
Applicable to	Applicable to Pro I/O Banks											
4 mA	-0.3	0.7	1.7	3.6	0.7	1.7	4	4	18	16	10	10
8 mA	-0.3	0.7	1.7	3.6	0.7	1.7	8	8	37	32	10	10
12 mA	-0.3	0.7	1.7	3.6	0.7	1.7	12	12	74	65	10	10
16 mA	-0.3	0.7	1.7	3.6	0.7	1.7	16	16	87	83	10	10
24 mA	-0.3	0.7	1.7	3.6	0.7	1.7	24	24	124	169	10	10
Applicable to	Advanced	I/O Bank	s		•					-		
2 mA	-0.3	0.7	1.7	2.7	0.7	1.7	2	2	18	16	10	10
4 mA	-0.3	0.7	1.7	2.7	0.7	1.7	4	4	18	16	10	10
6 mA	-0.3	0.7	1.7	2.7	0.7	1.7	6	6	37	32	10	10
8 mA	-0.3	0.7	1.7	2.7	0.7	1.7	8	8	37	32	10	10
12 mA	-0.3	0.7	1.7	2.7	0.7	1.7	12	12	74	65	10	10
16 mA	-0.3	0.7	1.7	2.7	0.7	1.7	16	16	87	83	10	10
24 mA	-0.3	0.7	1.7	2.7	0.7	1.7	24	24	124	169	10	10
Applicable to	Standard	I/O Banks						<u>.</u>				
2 mA	-0.3	0.7	1.7	3.6	0.7	1.7	2	2	18	16	10	10
4 mA	-0.3	0.7	1.7	3.6	0.7	1.7	4	4	18	16	10	10
6 mA	-0.3	0.7	1.7	3.6	0.7	1.7	6	6	37	32	10	10
8 mA	-0.3	0.7	1.7	3.6	0.7	1.7	8	8	37	32	10	10

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where –0.3 V < VIN < VIL.

2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges.

3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.

4. Currents are measured at 85°C junction temperature.

5. Software default selection highlighted in gray.



#### Figure 2-120 • AC Loading

Table 2-111 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	C <sub>LOAD</sub> (pF)
0	2.5	1.2	_	35

Note: \*Measuring point = Vtrip. See Table 2-90 on page 2-166 for a complete table of trip points.



#### Table 2-115 • 2.5 V LVCMOS High Slew

Commercial Temperature Range Conditions:  $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V Applicable to Advanced I/Os

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>zH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>zLS</sub>	t <sub>zHS</sub>	Units
4 mA	Std.	0.66	8.66	0.04	1.31	0.43	7.83	8.66	2.68	2.30	10.07	10.90	ns
	-1	0.56	7.37	0.04	1.11	0.36	6.66	7.37	2.28	1.96	8.56	9.27	ns
	-2	0.49	6.47	0.03	0.98	0.32	5.85	6.47	2.00	1.72	7.52	8.14	ns
8 mA	Std.	0.66	5.17	0.04	1.31	0.43	5.04	5.17	3.05	3.00	7.27	7.40	ns
	-1	0.56	4.39	0.04	1.11	0.36	4.28	4.39	2.59	2.55	6.19	6.30	ns
	-2	0.49	3.86	0.03	0.98	0.32	3.76	3.86	2.28	2.24	5.43	5.53	ns
12 mA	Std.	0.66	3.56	0.04	1.31	0.43	3.63	3.43	3.30	3.44	5.86	5.67	ns
	-1	0.56	3.03	0.04	1.11	0.36	3.08	2.92	2.81	2.92	4.99	4.82	ns
	-2	0.49	2.66	0.03	0.98	0.32	2.71	2.56	2.47	2.57	4.38	4.23	ns
16 mA	Std.	0.66	3.35	0.04	1.31	0.43	3.41	3.06	3.36	3.55	5.65	5.30	ns
	-1	0.56	2.85	0.04	1.11	0.36	2.90	2.60	2.86	3.02	4.81	4.51	ns
	-2	0.49	2.50	0.03	0.98	0.32	2.55	2.29	2.51	2.65	4.22	3.96	ns
24 mA	Std.	0.66	3.56	0.04	1.31	0.43	3.63	3.43	3.30	3.44	5.86	5.67	ns
	-1	0.56	3.03	0.04	1.11	0.36	3.08	2.92	2.81	2.92	4.99	4.82	ns
	-2	0.49	2.66	0.03	0.98	0.32	2.71	2.56	2.47	2.57	4.38	4.23	ns

Note: For the derating values at specific junction temperature and voltage supply levels, refer to Table 3-7 on page 3-9.

#### Table 2-116 • 2.5 V LVCMOS Low Slew

Commercial Temperature Range Conditions:  $T_J$  = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V Applicable to Standard I/Os

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>zH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	Units
2 mA	Std.	0.66	11.00	0.04	1.29	0.43	10.37	11.00	2.03	1.83	ns
	-1	0.56	9.35	0.04	1.10	0.36	8.83	9.35	1.73	1.56	ns
	-2	0.49	8.21	0.03	0.96	0.32	7.75	8.21	1.52	1.37	ns
4 mA	Std.	0.66	11.00	0.04	1.29	0.43	10.37	11.00	2.03	1.83	ns
	-1	0.56	9.35	0.04	1.10	0.36	8.83	9.35	1.73	1.56	ns
	-2	0.49	8.21	0.03	0.96	0.32	7.75	8.21	1.52	1.37	ns
6 mA	Std.	0.66	7.50	0.04	1.29	0.43	7.36	7.50	2.39	2.46	ns
	-1	0.56	6.38	0.04	1.10	0.36	6.26	6.38	2.03	2.10	ns
	-2	0.49	5.60	0.03	0.96	0.32	5.49	5.60	1.78	1.84	ns
8 mA	Std.	0.66	7.50	0.04	1.29	0.43	7.36	7.50	2.39	2.46	ns
	-1	0.56	6.38	0.04	1.10	0.36	6.26	6.38	2.03	2.10	ns
	-2	0.49	5.60	0.03	0.96	0.32	5.49	5.60	1.78	1.84	ns

Note: For the derating values at specific junction temperature and voltage supply levels, refer to Table 3-7 on page 3-9.



#### 1.8 V LVCMOS

Low-Voltage CMOS for 1.8 V is an extension of the LVCMOS standard (JESD8-5) used for generalpurpose 1.8 V applications. It uses a 1.8 V input buffer and push-pull output buffer.

1.8 V LVCMOS		VIL	VIH		VOL	VOH	IOL	юн	IOSL	IOSH	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
Applicable	Applicable to Pro I/O Banks											
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	2	2	11	9	10	10
4 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	4	4	22	17	10	10
6 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	6	6	44	35	10	10
8 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	8	8	51	45	10	10
12 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	12	12	74	91	10	10
16 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	16	16	74	91	10	10
Applicable	to Advar	nced I/O Banl	(S									
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI-0.45	2	2	11	9	10	10
4 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI-0.45	4	4	22	17	10	10
6 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI-0.45	6	6	44	35	10	10
8 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI-0.45	8	8	51	45	10	10
12 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI-0.45	12	12	74	91	10	10
16 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.9	0.45	VCCI-0.45	16	16	74	91	10	10
Applicable	to Stand	ard I/O Banks	5			•						
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	2	2	11	9	10	10
4 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI-0.45	4	4	22	17	10	10

#### Table 2-118 • Minimum and Maximum DC Input and Output Levels

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where –0.3 V < VIN < VIL.

2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges.

3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.

4. Currents are measured at 85°C junction temperature.

5. Software default selection highlighted in gray.



#### Figure 2-121 • AC Loading

#### Table 2-119 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input Low (V)	Measuring Point* (V)	VREF (typ.) (V)	C <sub>LOAD</sub> (pF)
0	1.8	0.9	-	35

Note: \*Measuring point = Vtrip. See Table 2-90 on page 2-166 for a complete table of trip points.



## Differential I/O Characteristics

Configuration of the I/O modules as a differential pair is handled by the Microsemi Designer software when the user instantiates a differential I/O macro in the design.

Differential I/Os can also be used in conjunction with the embedded Input Register (InReg), Output Register (OutReg), Enable Register (EnReg), and Double Data Rate (DDR). However, there is no support for bidirectional I/Os or tristates with these standards.

#### LVDS

Low-Voltage Differential Signal (ANSI/TIA/EIA-644) is a high-speed differential I/O standard. It requires that one data bit be carried through two signal lines, so two pins are needed. It also requires external resistor termination.

The full implementation of the LVDS transmitter and receiver is shown in an example in Figure 2-134. The building blocks of the LVDS transmitter–receiver are one transmitter macro, one receiver macro, three board resistors at the transmitter end, and one resistor at the receiver end. The values for the three driver resistors are different from those used in the LVPECL implementation because the output standard specifications are different.



Figure 2-134 • LVDS	<b>Circuit Diagram and</b>	Board-Level Implementatior
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Table 2-168 • I	Minimum and	Maximum	DC Input a	and Output Levels
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DC Parameter	Description	Min.	Тур.	Max.	Units
VCCI	Supply Voltage	2.375	2.5	2.625	V
VOL	Output Low Voltage	0.9	1.075	1.25	V
VOH	Input High Voltage	1.25	1.425	1.6	V
IOL <sup>1</sup>	Output Low Voltage	0.65	0.91	1.16	mA
IOH <sup>1</sup>	Output High Voltage	0.65	0.91	1.16	mA
VI	Input Voltage	0		2.925	V
IIL <sup>2,3</sup>	Input Low Voltage			10	μA
IIH <sup>2,4</sup>	Input High Voltage			10	μA
VODIFF	Differential Output Voltage	250	350	450	mV
VOCM	Output Common Mode Voltage	1.125	1.25	1.375	V
VICM	Input Common Mode Voltage	0.05	1.25	2.35	V
VIDIFF	Input Differential Voltage	100	350		mV

Notes:

- 1. IOL/IOH defined by VODIFF/(Resistor Network)
- 2. Currents are measured at 85°C junction temperature.
- 3. ILL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 4. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges.



#### TMS Test Mode Select

The TMS pin controls the use of the IEEE1532 boundary scan pins (TCK, TDI, TDO, TRST). There is an internal weak pull-up resistor on the TMS pin.

#### TRST Boundary Scan Reset Pin

The TRST pin functions as an active low input to asynchronously initialize (or reset) the boundary scan circuitry. There is an internal weak pull-up resistor on the TRST pin. If JTAG is not used, an external pull-down resistor could be included to ensure the TAP is held in reset mode. The resistor values must be chosen from Table 2-183 and must satisfy the parallel resistance value requirement. The values in Table 2-183 correspond to the resistor recommended when a single device is used and to the equivalent parallel resistor when multiple devices are connected via a JTAG chain.

In critical applications, an upset in the JTAG circuit could allow entering an undesired JTAG state. In such cases, Microsemi recommends tying off TRST to GND through a resistor placed close to the FPGA pin. Note that to operate at all VJTAG voltages, 500  $\Omega$  to 1 k $\Omega$  will satisfy the requirements.

## **Special Function Pins**

#### NC No Connect

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

#### DC Don't Connect

This pin should not be connected to any signals on the PCB. These pins should be left unconnected.

#### NCAP Negative Capacitor

Negative Capacitor is where the negative terminal of the charge pump capacitor is connected. A capacitor, with a 2.2  $\mu$ F recommended value, is required to connect between PCAP and NCAP.

#### PCAP Positive Capacitor

*Positive Capacitor* is where the positive terminal of the charge pump capacitor is connected. A capacitor, with a 2.2  $\mu$ F recommended value, is required to connect between PCAP and NCAP.

#### PUB Push Button

*Push button* is the connection for the external momentary switch used to turn on the 1.5 V voltage regulator and can be floating if not used.

#### PTBASE Pass Transistor Base

*Pass Transistor Base* is the control signal of the voltage regulator. This pin should be connected to the base of the external pass transistor used with the 1.5 V internal voltage regulator and can be floating if not used.

#### PTEM Pass Transistor Emitter

Pass Transistor Emitter is the feedback input of the voltage regulator.

This pin should be connected to the emitter of the external pass transistor used with the 1.5 V internal voltage regulator and can be floating if not used.

#### XTAL1 Crystal Oscillator Circuit Input

Input to crystal oscillator circuit. Pin for connecting external crystal, ceramic resonator, RC network, or external clock input. When using an external crystal or ceramic oscillator, external capacitors are also recommended (Please refer to the crystal oscillator manufacturer for proper capacitor value).

If using external RC network or clock input, XTAL1 should be used and XTAL2 left unconnected. In the case where the Crystal Oscillator block is not used, the XTAL1 pin should be connected to GND and the XTAL2 pin should be left floating.



Symbol	Parameter <sup>2</sup>		Commercial	Industrial	Units
Τ <sub>J</sub>	Junction temperature		0 to +85	-40 to +100	°C
VCC	1.5 V DC core supply voltage		1.425 to 1.575	1.425 to 1.575	V
VJTAG	JTAG DC voltage		1.4 to 3.6	1.4 to 3.6	V
VPUMP	Programming voltage	Programming mode <sup>3</sup>	3.15 to 3.45	3.15 to 3.45	V
		Operation <sup>4</sup>	0 to 3.6	0 to 3.6	V
VCCPLL	Analog power supply (PLL)		1.425 to 1.575	1.425 to 1.575	V
VCCI	1.5 V DC supply voltage	1.425 to 1.575	1.425 to 1.575	V	
	1.8 V DC supply voltage		1.7 to 1.9	1.7 to 1.9	V
	2.5 V DC supply voltage		2.3 to 2.7	2.3 to 2.7	V
	3.3 V DC supply voltage	3.0 to 3.6	3.0 to 3.6	V	
	LVDS differential I/O		2.375 to 2.625	2.375 to 2.625	V
	LVPECL differential I/O	3.0 to 3.6	3.0 to 3.6	V	
VCC33A	+3.3 V power supply		2.97 to 3.63	2.97 to 3.63	V
VCC33PMP	+3.3 V power supply	2.97 to 3.63	2.97 to 3.63	V	
VAREF	Voltage reference for ADC	2.527 to 2.593	2.527 to 2.593	V	
VCC15A <sup>5</sup>	Digital power supply for the analog	1.425 to 1.575	1.425 to 1.575	V	
VCCNVM	Embedded flash power supply		1.425 to 1.575	1.425 to 1.575	V
VCCOSC	Oscillator power supply		2.97 to 3.63	2.97 to 3.63	V
AV, AC <sup>6</sup>	Unpowered, ADC reset asserted or	-10.5 to 12.0	-10.5 to 11.6	V	
	Analog input (+16 V to +2 V presca	ller range)	-0.3 to 12.0	–0.3 to 11.6	V
	Analog input (+1 V to + 0.125 V pre	escaler range)	-0.3 to 3.6	-0.3 to 3.6	V
	Analog input (–16 V to –2 V presca	-10.5 to 0.3	-10.5 to 0.3	V	
	Analog input (–1 V to –0.125 V pres	-3.6 to 0.3	-3.6 to 0.3	V	
	Analog input (direct input to ADC)	-0.3 to 3.6	-0.3 to 3.6	V	
	Digital input		-0.3 to 12.0	–0.3 to 11.6	V
AG <sup>6</sup>	Unpowered, ADC reset asserted or	-10.5 to 12.0	-10.5 to 11.6	V	
	Low Current Mode (1 µA, 3 µA, 10	-0.3 to 12.0	–0.3 to 11.6	V	
	Low Current Mode (–1 µA, –3 µA, -	-10.5 to 0.3	-10.5 to 0.3	V	
	High Current Mode <sup>7</sup>	-10.5 to 12.0	-10.5 to 11.6	V	
AT <sup>6</sup>	Unpowered, ADC reset asserted or	-0.3 to 15.5	–0.3 to 14.5	V	
	Analog input (+16 V, +4 V prescale	-0.3 to 15.5	–0.3 to 14.5	V	
	Analog input (direct input to ADC)	-0.3 to 3.6	-0.3 to 3.6	V	
	Digital input		-0.3 to 15.5	-0.3 to 14.5	V

#### Table 3-2 • Recommended Operating Conditions<sup>1</sup>

Notes:

1. The ranges given here are for power supplies only. The recommended input voltage ranges specific to each I/O standard are given in Table 2-85 on page 2-157.

- 2. All parameters representing voltages are measured with respect to GND unless otherwise specified.
- 3. The programming temperature range supported is  $T_{ambient} = 0^{\circ}C$  to 85°C.
- 4. VPUMP can be left floating during normal operation (not programming mode).
- 5. Violating the V<sub>CC15A</sub> recommended voltage supply during an embedded flash program cycle can corrupt the page being programmed.
- 6. The input voltage may overshoot by up to 500 mV above the Recommended Maximum (150 mV in Direct mode), provided the duration of the overshoot is less than 50% of the operating lifetime of the device.
- 7. The AG pad should also conform to the limits as specified in Table 2-48 on page 2-114.



#### Total Static Power Consumption—PSTAT

Number of Quads used:  $N_{QUADS} = 4$ Number of NVM blocks available (AFS600):  $N_{NVM-BLOCKS} = 2$ Number of input pins used:  $N_{INPUTS} = 30$ Number of output pins used:  $N_{OUTPUTS} = 40$ 

#### **Operating Mode**

 $\mathsf{P}_{\mathsf{STAT}} = \mathsf{PDC1} + (\mathsf{N}_{\mathsf{NVM-BLOCKS}} * \mathsf{PDC4}) + \mathsf{PDC5} + (\mathsf{N}_{\mathsf{QUADS}} * \mathsf{PDC6}) + (\mathsf{N}_{\mathsf{INPUTS}} * \mathsf{PDC7}) + (\mathsf{N}_{\mathsf{OUTPUTS}} * \mathsf{PDC8})$ 

P<sub>STAT</sub> = 7.50 mW + (2 \* 1.19 mW) + 8.25 mW + (4 \* 3.30 mW) + (30 \* 0.00) + (40 \* 0.00)

P<sub>STAT</sub> = 31.33 mW

#### Standby Mode

P<sub>STAT</sub> = PDC2

 $P_{STAT}$  = 0.03 mW

#### Sleep Mode

 $P_{STAT} = PDC3$ 

 $P_{STAT} = 0.03 \text{ mW}$ 

#### Total Power Consumption—PTOTAL

In operating mode, the total power consumption of the device is 174.39 mW:

 $P_{TOTAL} = P_{STAT} + P_{DYN}$ 

P<sub>TOTAL</sub> = 143.06 mW + 31.33 mW

P<sub>TOTAL</sub> = 174.39 mW

In standby mode, the total power consumption of the device is limited to 0.66 mW:

 $P_{TOTAL} = P_{STAT} + P_{DYN}$ 

 $P_{TOTAL} = 0.03 \text{ mW} + 0.63 \text{ mW}$ 

 $P_{TOTAL} = 0.66 \text{ mW}$ 

In sleep mode, the total power consumption of the device drops as low as 0.03 mW:

 $P_{TOTAL} = P_{STAT} + P_{DYN}$  $P_{TOTAL} = 0.03 \text{ mW}$ 

Fusion Family of Mixed Signal FPGAs

PQ208			PQ208			
Pin Number	AFS250 Function	AFS600 Function	Pin Number	AFS250 Function	AFS600 Function	
74	AV2	AV4	111	VCCNVM	VCCNVM	
75	AC2	AC4	112	VCC	VCC	
76	AG2	AG4	112	VCC	VCC	
77	AT2	AT4	113	VPUMP	VPUMP	
78	ATRTN1	ATRTN2	114	GNDQ	NC	
79	AT3	AT5	115	VCCIB1	ТСК	
80	AG3	AG5	116	ТСК	TDI	
81	AC3	AC5	117	TDI	TMS	
82	AV3	AV5	118	TMS	TDO	
83	AV4	AV6	119	TDO	TRST	
84	AC4	AC6	120	TRST	VJTAG	
85	AG4	AG6	121	VJTAG	IO57NDB2V0	
86	AT4	AT6	122	IO57NDB1V0	GDC2/IO57PDB2V0	
87	ATRTN2	ATRTN3	123	GDC2/IO57PDB1V0	IO56NDB2V0	
88	AT5	AT7	124	IO56NDB1V0	GDB2/IO56PDB2V0	
89	AG5	AG7	125	GDB2/IO56PDB1V0	IO55NDB2V0	
90	AC5	AC7	126	VCCIB1	GDA2/IO55PDB2V0	
91	AV5	AV7	127	GND	GDA0/IO54NDB2V0	
92	NC	AV8	128	IO55NDB1V0	GDA1/IO54PDB2V0	
93	NC	AC8	129	GDA2/IO55PDB1V0	VCCIB2	
94	NC	AG8	130	GDA0/IO54NDB1V0	GND	
95	NC	AT8	131	GDA1/IO54PDB1V0	VCC	
96	NC	ATRTN4	132	GDB0/IO53NDB1V0	GCA0/IO45NDB2V0	
97	NC	AT9	133	GDB1/IO53PDB1V0	GCA1/IO45PDB2V0	
98	NC	AG9	134	GDC0/IO52NDB1V0	GCB0/IO44NDB2V0	
99	NC	AC9	135	GDC1/IO52PDB1V0	GCB1/IO44PDB2V0	
100	NC	AV9	136	IO51NSB1V0	GCC0/IO43NDB2V	
101	GNDAQ	GNDAQ			0	
102	VCC33A	VCC33A	137	VCCIB1	GCC1/IO43PDB2V0	
103	ADCGNDREF	ADCGNDREF	138	GND	IO42NDB2V0	
104	VAREF	VAREF	139	VCC	IO42PDB2V0	
105	PUB	PUB	140	IO50NDB1V0	IO41NDB2V0	
106	VCC33A	VCC33A	141	IO50PDB1V0	GCC2/IO41PDB2V0	
107	GNDA	GNDA	142	GCA0/IO49NDB1V0	VCCIB2	
108	PTEM	PTEM	143	GCA1/IO49PDB1V0	GND	
109	PTBASE	PTBASE	144	GCB0/IO48NDB1V0	VCC	
110	GNDNVM	GNDNVM	145	GCB1/IO48PDB1V0	IO40NDB2V0	
		L]	146	GCC0/IO47NDB1V0	GCB2/IO40PDB2V0	

FG256					
Pin Number	AFS090 Function	AFS250 Function	AFS600 Function	AFS1500 Function	
E13	VCCIB1	VCCIB1	VCCIB2	VCCIB2	
E14	GCC2/IO33NDB1V0	IO42NDB1V0	IO32NDB2V0	IO46NDB2V0	
E15	GCB2/IO33PDB1V0	GBC2/IO42PDB1V0	GBC2/IO32PDB2V0	GBC2/IO46PDB2V0	
E16	GND	GND	GND	GND	
F1	NC	NC	IO79NDB4V0	IO111NDB4V0	
F2	NC	NC	IO79PDB4V0	IO111PDB4V0	
F3	GFB1/IO48PPB3V0	IO72NDB3V0	IO76NDB4V0	IO112NDB4V0	
F4	GFC0/IO49NDB3V0	IO72PDB3V0	IO76PDB4V0	IO112PDB4V0	
F5	NC	NC	IO82PSB4V0	IO120PSB4V0	
F6	GFC1/IO49PDB3V0	GAC2/IO74PPB3V0	GAC2/IO83PPB4V0	GAC2/IO123PPB4V0	
F7	NC	IO09RSB0V0	IO04PPB0V0	IO05PPB0V1	
F8	NC	IO19RSB0V0	IO08NDB0V1	IO11NDB0V1	
F9	NC	NC	IO20PDB1V0	IO27PDB1V1	
F10	NC	IO29RSB0V0	IO23NDB1V1	IO37NDB1V2	
F11	NC	IO43NDB1V0	IO36NDB2V0	IO50NDB2V0	
F12	NC	IO43PDB1V0	IO36PDB2V0	IO50PDB2V0	
F13	NC	IO44NDB1V0	IO39NDB2V0	IO59NDB2V0	
F14	NC	GCA2/IO44PDB1V0	GCA2/IO39PDB2V0	GCA2/IO59PDB2V0	
F15	GCC1/IO34PDB1V0	GCB2/IO45PDB1V0	GCB2/IO40PDB2V0	GCB2/IO60PDB2V0	
F16	GCC0/IO34NDB1V0	IO45NDB1V0	IO40NDB2V0	IO60NDB2V0	
G1	GEC0/IO46NPB3V0	IO70NPB3V0	IO74NPB4V0	IO109NPB4V0	
G2	VCCIB3	VCCIB3	VCCIB4	VCCIB4	
G3	GEC1/IO46PPB3V0	GFB2/IO70PPB3V0	GFB2/IO74PPB4V0	GFB2/IO109PPB4V0	
G4	GFA1/IO47PDB3V0	GFA2/IO71PDB3V0	GFA2/IO75PDB4V0	GFA2/IO110PDB4V0	
G5	GND	GND	GND	GND	
G6	GFA0/IO47NDB3V0	IO71NDB3V0	IO75NDB4V0	IO110NDB4V0	
G7	GND	GND	GND	GND	
G8	VCC	VCC	VCC	VCC	
G9	GND	GND	GND	GND	
G10	VCC	VCC	VCC	VCC	
G11	GDA1/IO37NDB1V0	GCC0/IO47NDB1V0	GCC0/IO43NDB2V0	GCC0/IO62NDB2V0	
G12	GND	GND	GND	GND	
G13	IO37PDB1V0	GCC1/IO47PDB1V0	GCC1/IO43PDB2V0	GCC1/IO62PDB2V0	
G14	GCB0/IO35NPB1V0	IO46NPB1V0	IO41NPB2V0	IO61NPB2V0	
G15	VCCIB1	VCCIB1	VCCIB2	VCCIB2	
G16	GCB1/IO35PPB1V0	GCC2/IO46PPB1V0	GCC2/IO41PPB2V0	GCC2/IO61PPB2V0	
H1	GEB1/IO45PDB3V0	GFC2/IO69PDB3V0	GFC2/IO73PDB4V0	GFC2/IO108PDB4V0	
H2	GEB0/IO45NDB3V0	IO69NDB3V0	IO73NDB4V0	IO108NDB4V0	

FG484			FG484			
Pin Number	AFS600 Function	AFS1500 Function	Pin Number	AFS600 Function	AFS1500 Function	
H13	GND	GND	K4	IO75NDB4V0	IO110NDB4V0	
H14	VCCIB1	VCCIB1	K5	GND	GND	
H15	GND	GND	K6	NC	IO104NDB4V0	
H16	GND	GND	K7	NC	IO111NDB4V0	
H17	NC	IO53NDB2V0	K8	GND	GND	
H18	IO38PDB2V0	IO57PDB2V0	K9	VCC	VCC	
H19	GCA2/IO39PDB2V0	GCA2/IO59PDB2V0	K10	GND	GND	
H20	VCCIB2	VCCIB2	K11	VCC	VCC	
H21	IO37NDB2V0	IO54NDB2V0	K12	GND	GND	
H22	IO37PDB2V0	IO54PDB2V0	K13	VCC	VCC	
J1	NC	IO112PPB4V0	K14	GND	GND	
J2	IO76NDB4V0	IO113NDB4V0	K15	GND	GND	
J3	GFB2/IO74PDB4V0	GFB2/IO109PDB4V0	K16	IO40NDB2V0	IO60NDB2V0	
J4	GFA2/IO75PDB4V0	GFA2/IO110PDB4V0	K17	NC	IO58PDB2V0	
J5	NC	IO112NPB4V0	K18	GND	GND	
J6	NC	IO104PDB4V0	K19	NC	IO68NPB2V0	
J7	NC	IO111PDB4V0	K20	IO41NDB2V0	IO61NDB2V0	
J8	VCCIB4	VCCIB4	K21	GND	GND	
J9	GND	GND	K22	IO42NDB2V0	IO56NDB2V0	
J10	VCC	VCC	L1	IO73NDB4V0	IO108NDB4V0	
J11	GND	GND	L2	VCCOSC	VCCOSC	
J12	VCC	VCC	L3	VCCIB4	VCCIB4	
J13	GND	GND	L4	XTAL2	XTAL2	
J14	VCC	VCC	L5	GFC1/IO72PDB4V0	GFC1/IO107PDB4V0	
J15	VCCIB2	VCCIB2	L6	VCCIB4	VCCIB4	
J16	GCB2/IO40PDB2V0	GCB2/IO60PDB2V0	L7	GFB1/IO71PDB4V0	GFB1/IO106PDB4V0	
J17	NC	IO58NDB2V0	L8	VCCIB4	VCCIB4	
J18	IO38NDB2V0	IO57NDB2V0	L9	GND	GND	
J19	IO39NDB2V0	IO59NDB2V0	L10	VCC	VCC	
J20	GCC2/IO41PDB2V0	GCC2/IO61PDB2V0	L11	GND	GND	
J21	NC	IO55PSB2V0	L12	VCC	VCC	
J22	IO42PDB2V0	IO56PDB2V0	L13	GND	GND	
K1	GFC2/IO73PDB4V0	GFC2/IO108PDB4V0	L14	VCC	VCC	
K2	GND	GND	L15	VCCIB2	VCCIB2	
K3	IO74NDB4V0	IO109NDB4V0	L16	IO48PDB2V0	IO70PDB2V0	



Package Pin Assignments

FG484			FG484			
Pin Number	AFS600 Function	AFS1500 Function	Pin Number	AFS600 Function	AFS1500 Function	
L17	VCCIB2	VCCIB2	N8	GND	GND	
L18	IO46PDB2V0	IO69PDB2V0	N9	GND	GND	
L19	GCA1/IO45PDB2V0	GCA1/IO64PDB2V0	N10	VCC	VCC	
L20	VCCIB2	VCCIB2	N11	GND	GND	
L21	GCC0/IO43NDB2V0	GCC0/IO62NDB2V0	N12	VCC	VCC	
L22	GCC1/IO43PDB2V0	GCC1/IO62PDB2V0	N13	GND	GND	
M1	NC	IO103PDB4V0	N14	VCC	VCC	
M2	XTAL1	XTAL1	N15	GND	GND	
M3	VCCIB4	VCCIB4	N16	GDB2/IO56PDB2V0	GDB2/IO83PDB2V0	
M4	GNDOSC	GNDOSC	N17	NC	IO78PDB2V0	
M5	GFC0/IO72NDB4V0	GFC0/IO107NDB4V0	N18	GND	GND	
M6	VCCIB4	VCCIB4	N19	IO47NDB2V0	IO72NDB2V0	
M7	GFB0/IO71NDB4V0	GFB0/IO106NDB4V0	N20	IO47PDB2V0	IO72PDB2V0	
M8	VCCIB4	VCCIB4	N21	GND	GND	
M9	VCC	VCC	N22	IO49PDB2V0	IO71PDB2V0	
M10	GND	GND	P1	GFA1/IO70PDB4V0	GFA1/IO105PDB4V0	
M11	VCC	VCC	P2	GFA0/IO70NDB4V0	GFA0/IO105NDB4V0	
M12	GND	GND	P3	IO68NDB4V0	IO101NDB4V0	
M13	VCC	VCC	P4	IO65PDB4V0	IO96PDB4V0	
M14	GND	GND	P5	IO65NDB4V0	IO96NDB4V0	
M15	VCCIB2	VCCIB2	P6	NC	IO99NDB4V0	
M16	IO48NDB2V0	IO70NDB2V0	P7	NC	IO97NDB4V0	
M17	VCCIB2	VCCIB2	P8	VCCIB4	VCCIB4	
M18	IO46NDB2V0	IO69NDB2V0	P9	VCC	VCC	
M19	GCA0/IO45NDB2V0	GCA0/IO64NDB2V0	P10	GND	GND	
M20	VCCIB2	VCCIB2	P11	VCC	VCC	
M21	GCB0/IO44NDB2V0	GCB0/IO63NDB2V0	P12	GND	GND	
M22	GCB1/IO44PDB2V0	GCB1/IO63PDB2V0	P13	VCC	VCC	
N1	NC	IO103NDB4V0	P14	GND	GND	
N2	GND	GND	P15	VCCIB2	VCCIB2	
N3	IO68PDB4V0	IO101PDB4V0	P16	IO56NDB2V0	IO83NDB2V0	
N4	NC	IO100NPB4V0	P17	NC	IO78NDB2V0	
N5	GND	GND	P18	GDA1/IO54PDB2V0	GDA1/IO81PDB2V0	
N6	NC	IO99PDB4V0	P19	GDB1/IO53PDB2V0	GDB1/IO80PDB2V0	
N7	NC	IO97PDB4V0	P20	IO51NDB2V0	IO73NDB2V0	

Fusion Family of Mixed Signal FPGAs

FG676		FG676		FG676	
Pin Number	AFS1500 Function	Pin Number	AFS1500 Function	Pin Number	AFS1500 Function
R21	IO72NDB2V0	U5	VCCIB4	V15	AC5
R22	IO72PDB2V0	U6	IO91PDB4V0	V16	NC
R23	GND	U7	IO91NDB4V0	V17	GNDA
R24	IO71PDB2V0	U8	IO92PDB4V0	V18	IO77PPB2V0
R25	VCCIB2	U9	GND	V19	IO74PDB2V0
R26	IO67NDB2V0	U10	GND	V20	VCCIB2
T1	GND	U11	VCC33A	V21	IO82NDB2V0
T2	NC	U12	GNDA	V22	GDA2/IO82PDB2V0
Т3	GFA1/IO105PDB4V0	U13	VCC33A	V23	GND
T4	GFA0/IO105NDB4V0	U14	GNDA	V24	GDC1/IO79PDB2V0
T5	IO101NDB4V0	U15	VCC33A	V25	VCCIB2
Т6	IO96PDB4V0	U16	GNDA	V26	NC
Τ7	IO96NDB4V0	U17	VCC	W1	GND
Т8	IO99NDB4V0	U18	GND	W2	IO94PPB4V0
Т9	IO97NDB4V0	U19	IO74NDB2V0	W3	IO98PDB4V0
T10	VCCIB4	U20	GDA0/IO81NDB2V0	W4	IO98NDB4V0
T11	VCC	U21	GDB0/IO80NDB2V0	W5	GEC1/IO90PDB4V0
T12	GND	U22	VCCIB2	W6	GEC0/IO90NDB4V0
T13	VCC	U23	IO75NDB2V0	W7	GND
T14	GND	U24	IO75PDB2V0	W8	VCCNVM
T15	VCC	U25	NC	W9	VCCIB4
T16	GND	U26	NC	W10	VCC15A
T17	VCCIB2	V1	NC	W11	GNDA
T18	IO83NDB2V0	V2	VCCIB4	W12	AC4
T19	IO78NDB2V0	V3	IO100PPB4V0	W13	VCC33A
T20	GDA1/IO81PDB2V0	V4	GND	W14	GNDA
T21	GDB1/IO80PDB2V0	V5	IO95PDB4V0	W15	AG5
T22	IO73NDB2V0	V6	IO95NDB4V0	W16	GNDA
T23	IO73PDB2V0	V7	VCCIB4	W17	PUB
T24	IO71NDB2V0	V8	IO92NDB4V0	W18	VCCIB2
T25	NC	V9	GNDNVM	W19	TDI
T26	GND	V10	GNDA	W20	GND
U1	NC	V11	NC	W21	IO84NDB2V0
U2	NC	V12	AV4	W22	GDC2/IO84PDB2V0
U3	IO102PDB4V0	V13	NC	W23	IO77NPB2V0
U4	IO102NDB4V0	V14	AV5	W24	GDC0/IO79NDB2V0